

**Search Notes**

Application/Control No.

10/700,279

Examiner

Tamai IE Karl

Applicant(s)/Patent under  
Reexamination

YAN ET AL.

Art Unit

2834

**SEARCHED**

Class	Subclass	Date	Examiner
310	309, 40mm		
359	223-226		
	291	06/11/05	bu

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR